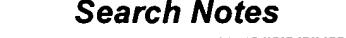


Search Notes 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/532,129	BEAUGE ET AL.
	Examiner	Art Unit
	Diem Tran	3748

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner